

RD53A CALIBRATION

MARCH 2021

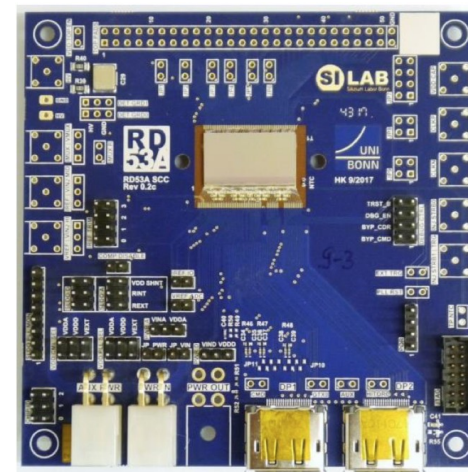
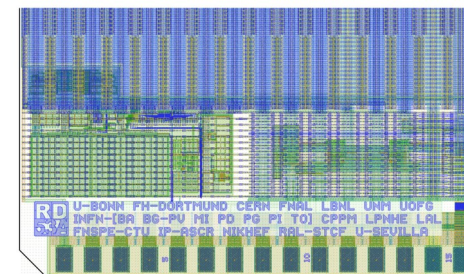
Natalia Emriskova
Stefano Mersi

RD53A PIXEL CHIP



RD53A Specifications

Technology	TSMC 65 nm CMOS
Pixel size	$50 \times 50 \mu\text{m}^2$
Chip size	$20 \times 11.8 \text{ mm}^2$ Half size of the final CMS chip
Number of pixels	$400 \times 192 = 76800$ Final CMS chip: $432 \times 336 = 145152$
Detector capacitance	$< 100 \text{ fF}$
Leakage current	$< 10 \text{ nA}$
(In-time) threshold	$(1200e^-) 600e^-$
Noise hits	$< 10^{-6}$
Radiation tolerance	500 Mrad at -12°C
Temperature	$[-40^\circ\text{C}; +40^\circ\text{C}]$



FLOORPLAN



Top test pad

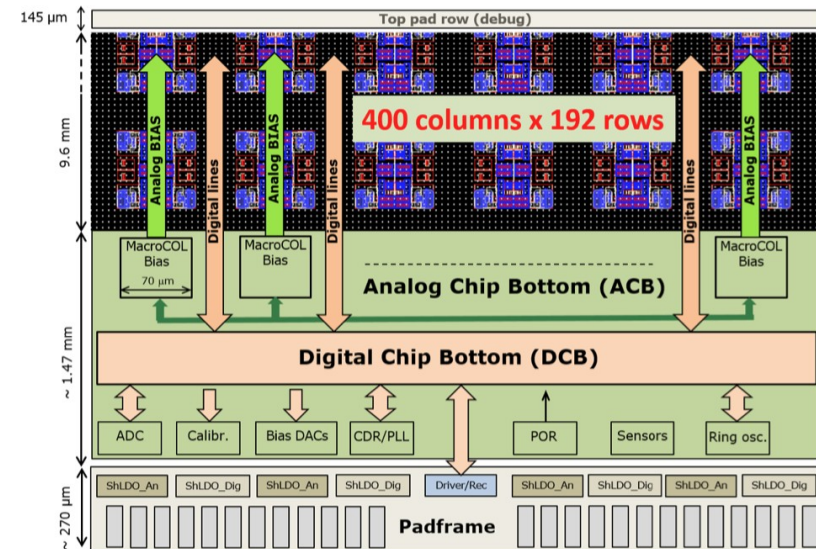
- Row of test pads for debugging purposes
- Will be removed in the production chip

Pixel matrix

- $192 \times 400 = 76\,800$ pixels

Chip Bottom

- all global analog and digital circuitry needed to bias, configure, monitor and readout the chip



FLOORPLAN



Top test pad

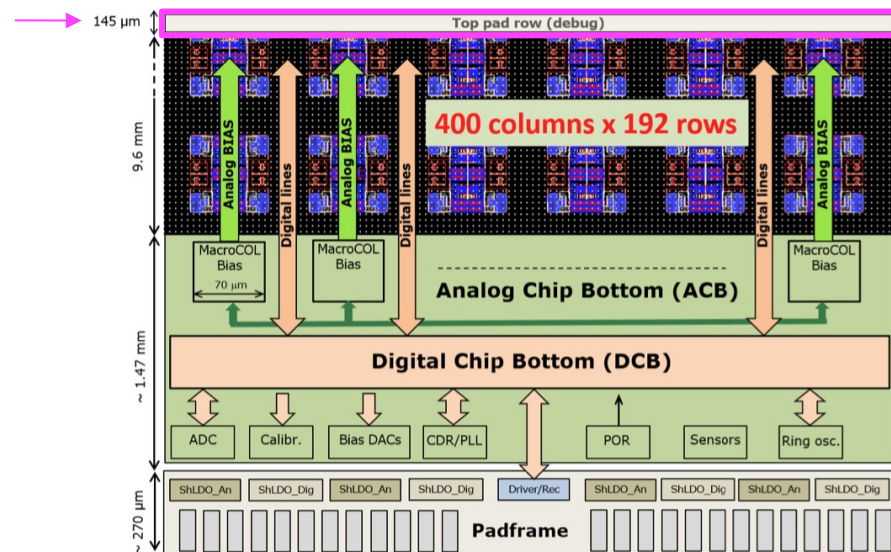
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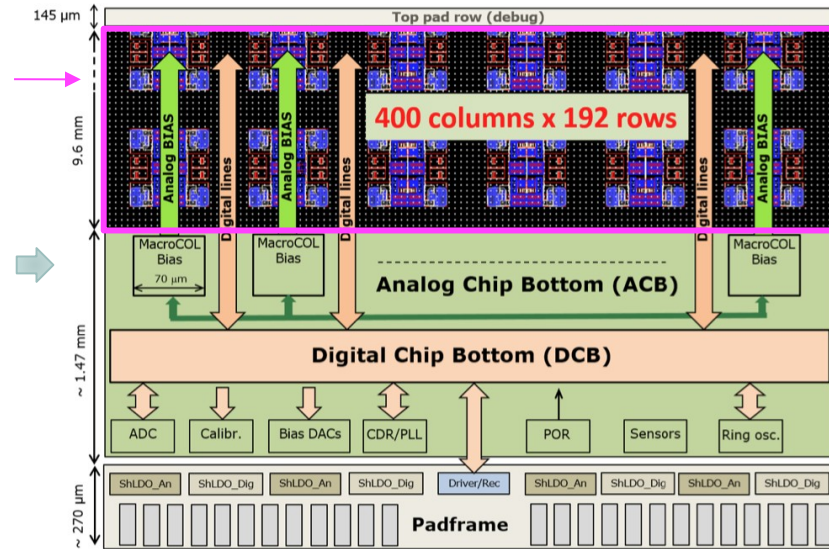
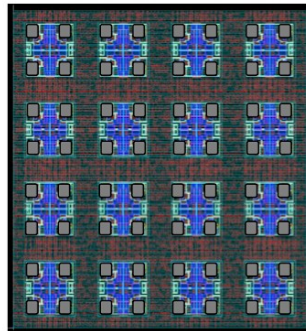
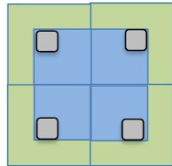
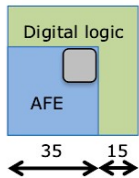
- $192 \times 400 = 76\,800$ pixels

Chip Bottom

- all global analog and digital circuitry needed to bias, configure, monitor and readout the chip



FLOORPLAN



Pixel

50% Analog
50% Digital
+ Bump pad

Analog island

2x2 pixel
quad

Pixel core

16 analog islands
in a fully
synthesized
digital sea

Pixel matrix

All cores the
same

FLOORPLAN



Power distribution

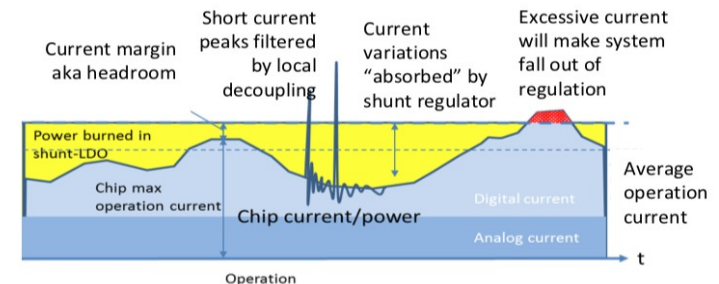
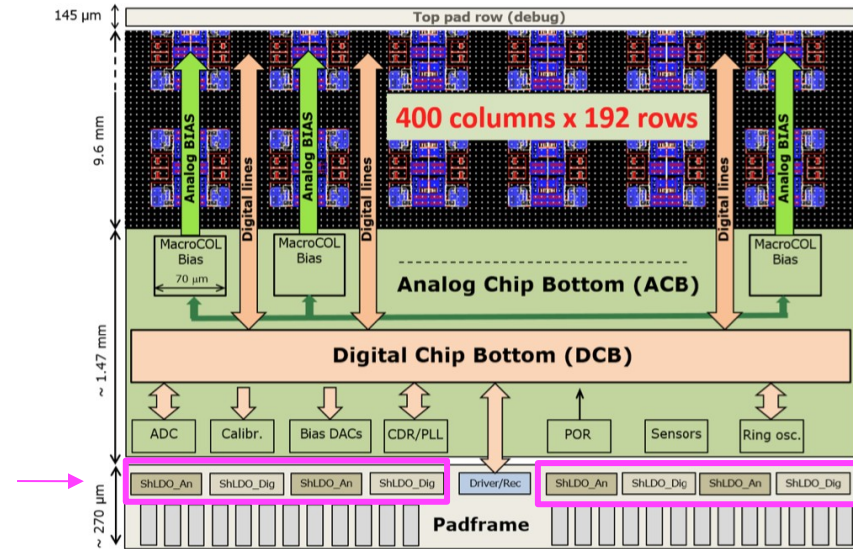
- Power lines distributed from the bottom to the whole chip

Serial powering

- Baseline powering scheme for CMS and ATLAS HL-LHC pixel detectors
- Pixel modules powered in series (chips in a module powered in parallel)

Shunt-LDO regulator

- 2 Shunt-LDO regulators (1 analog + 1 digital)
- supply **constant input current independent of the load**
- excess current is shunted to ground** (headroom)



RD53A manual:

https://cds.cern.ch/record/2287593/files/%20RD53A_Manual_V3-42.pdf

FLOORPLAN



Analog chip bottom (ACB)

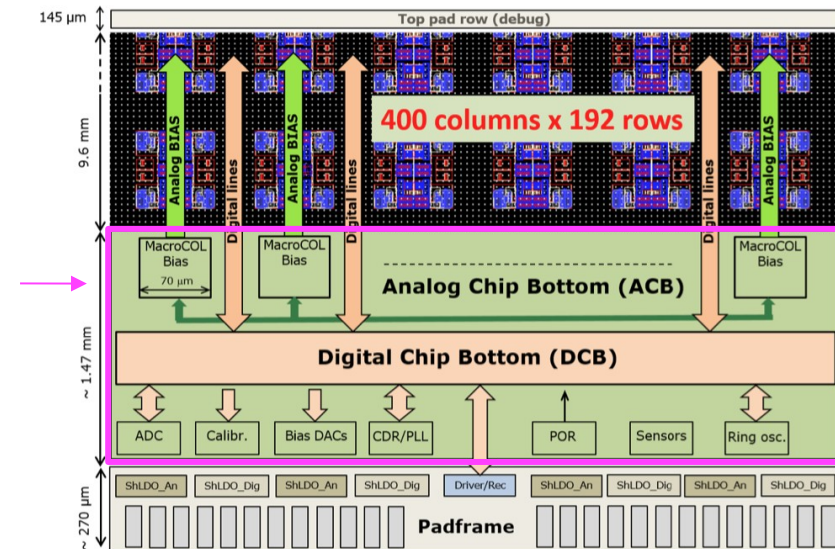
- Providing current reference DACs (I_{ref}) and voltage levels to the calibration injection circuit
- Monitoring: temperature, radiation, currents, voltages
- CDR/PLL recovers data and clock from input stream at 160 Mbps

Digital chip bottom (DCB)

- Control and processing functionalities
- Input, Output and Configuration digital logic

Output Serializer & CML cable drivers

- 4 Aurora lanes at 1.28 Gbps
- CML output driver with programmable pre-emphasis

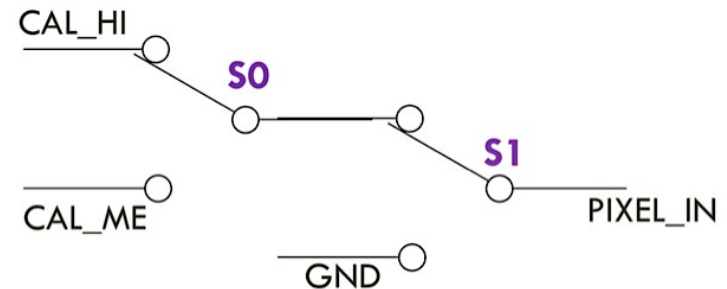
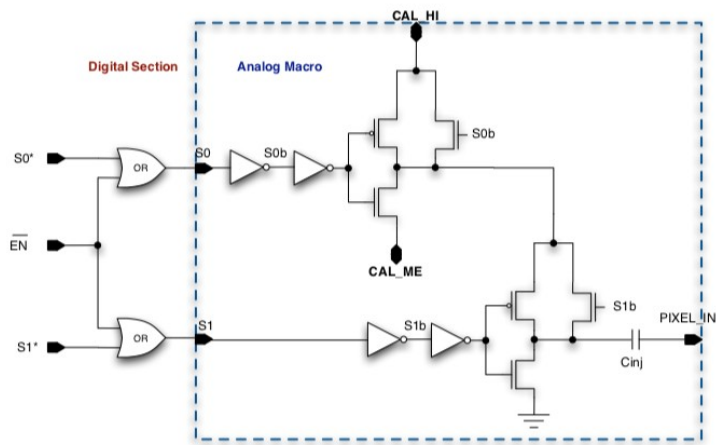


CALIBRATION INJECTION CIRCUIT

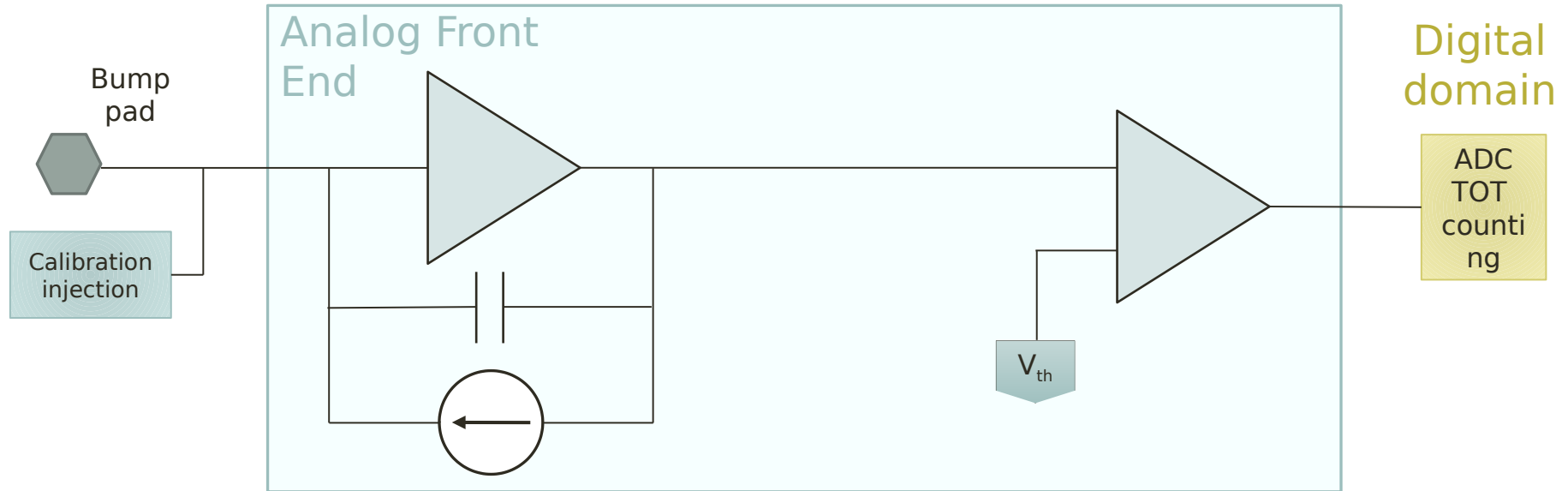
Calibration injection circuit

- Present in each pixel, picks charge from global voltage sources
- Same across the whole chip
- Equivalent to 2 switches
 - controlled by 2 control signals (S0 and S1)
 - switching between 3 voltage levels (CAL_HIGH, CAL_MED and GND)

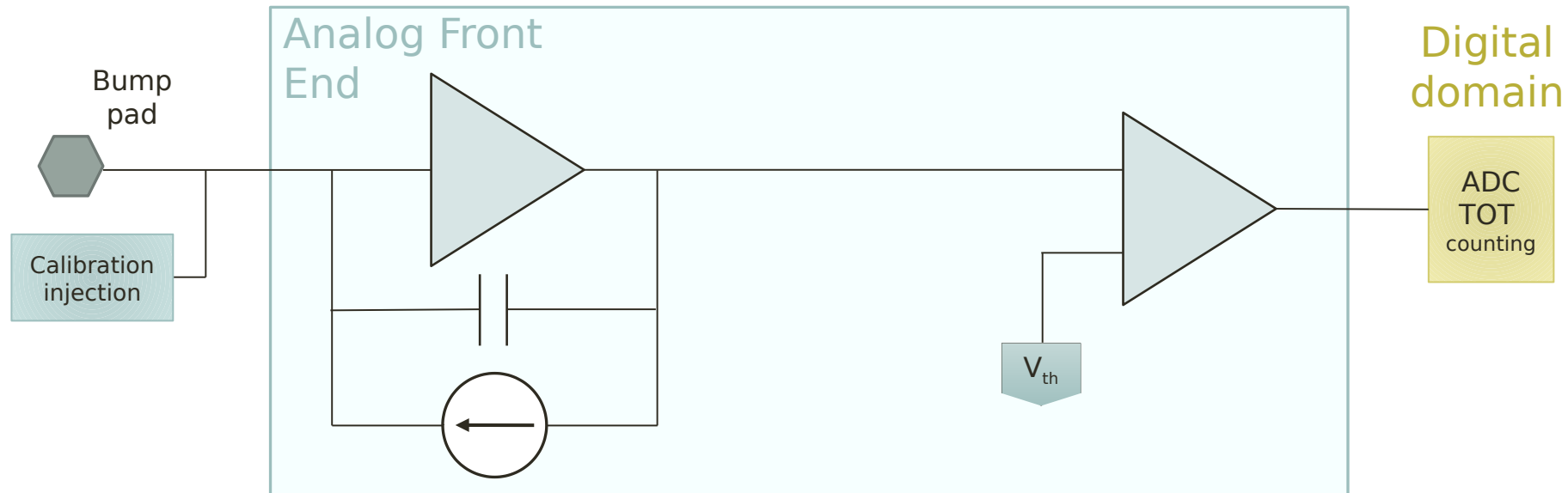
→ injection of a known charge to pixels



ANALOG FRONT-END BASICS

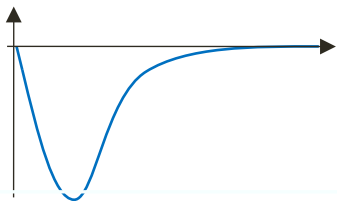


ANALOG FRONT-END BASICS

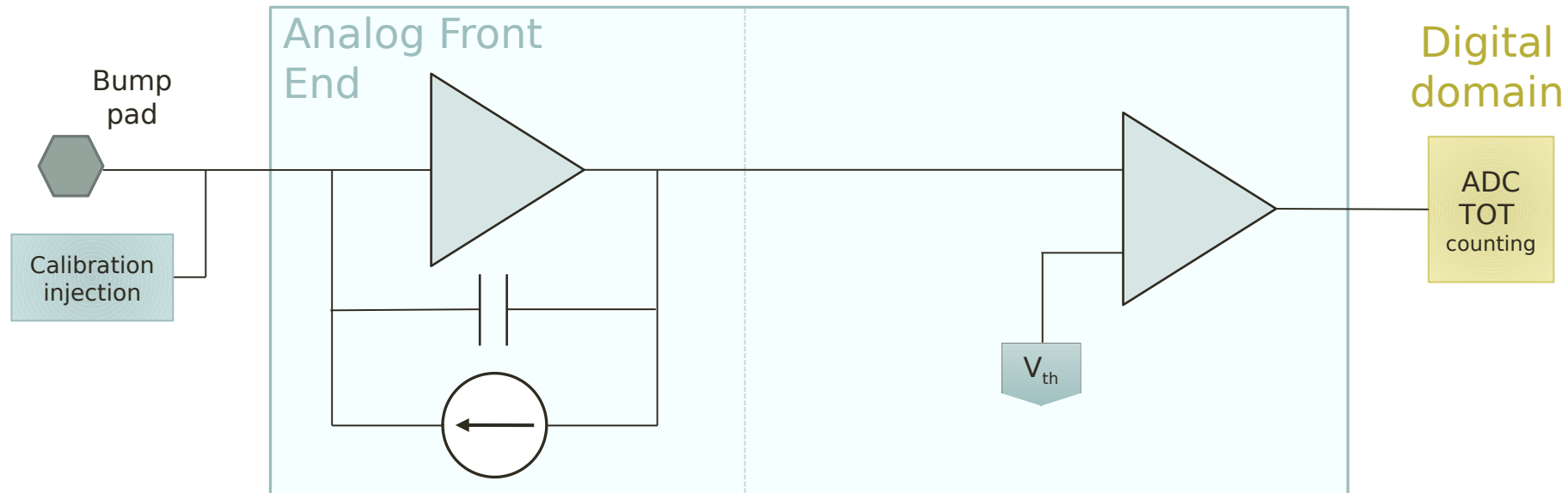


Signal collection

Negative signal arriving from the sensor or from injection circuit

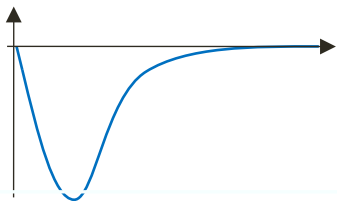


ANALOG FRONT-END BASICS



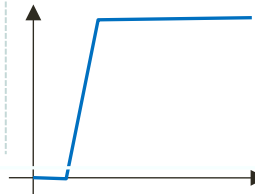
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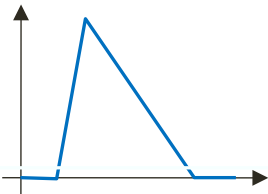
Pre-amplifier

Converts arriving signal in a voltage step

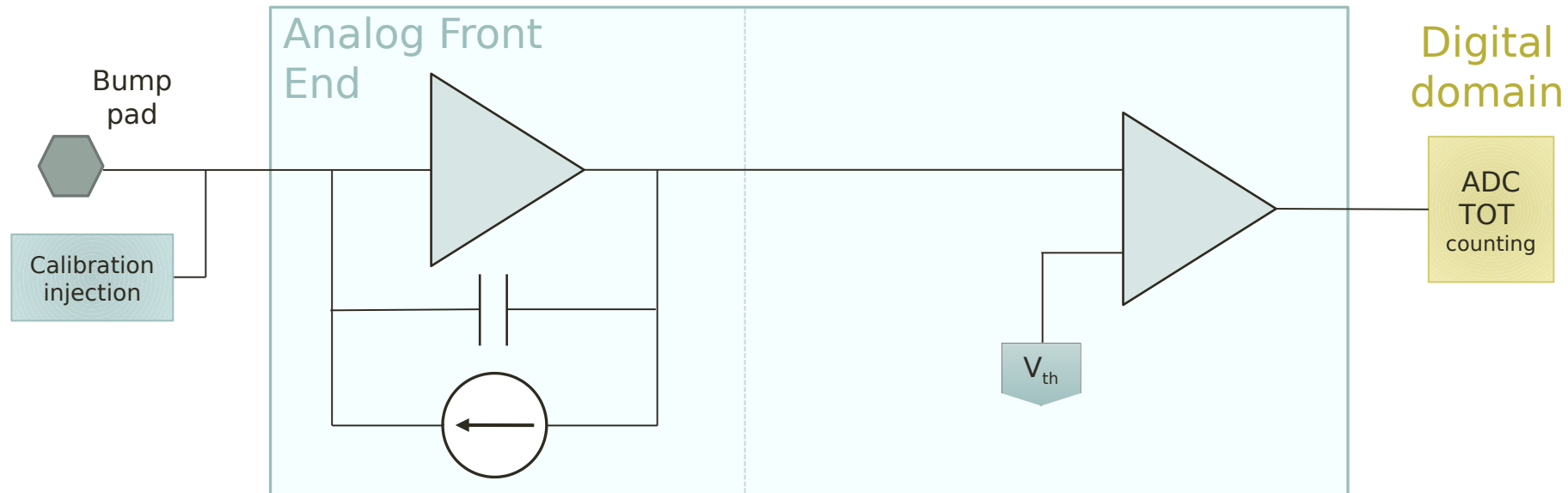


Feedback loop

Discharges the preamplifier after signal rise

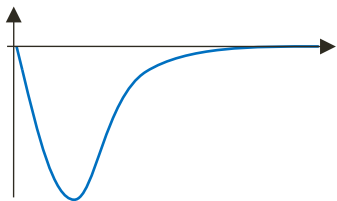


ANALOG FRONT-END BASICS



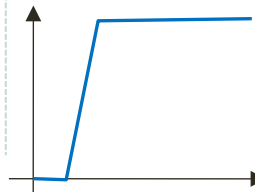
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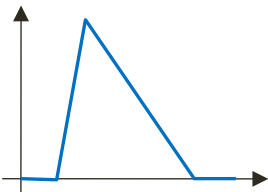
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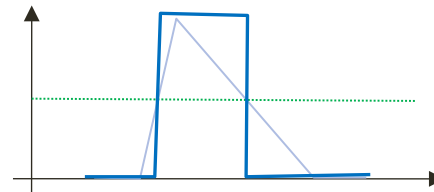
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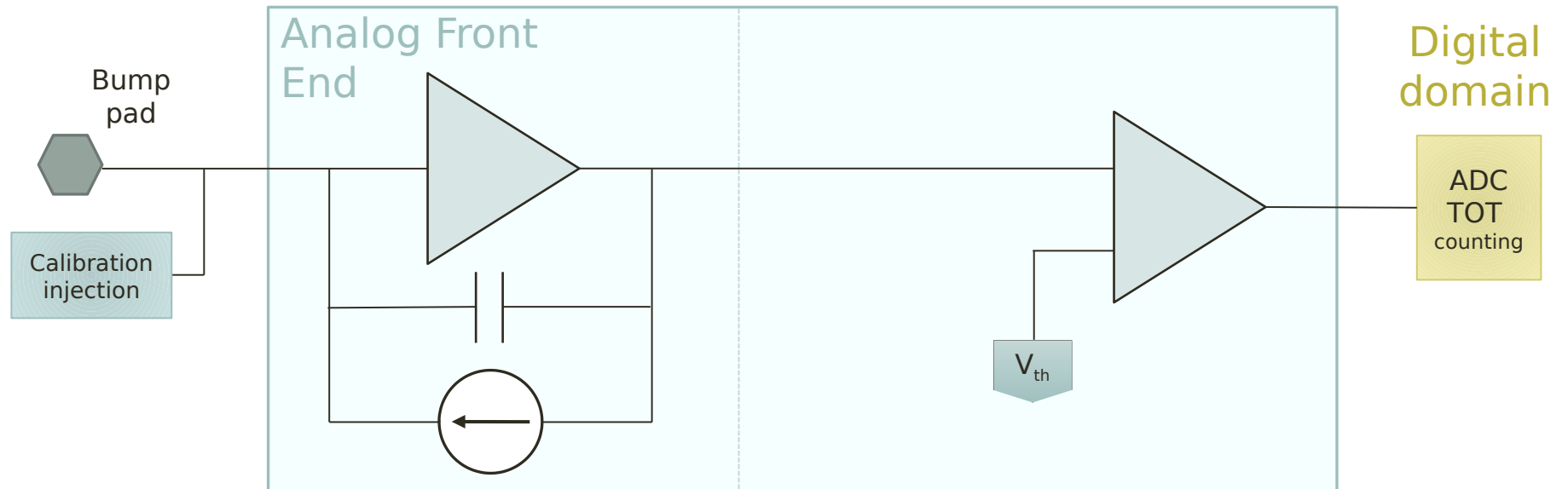


Comparator

Compares the signal with the threshold to determine if there was a hit

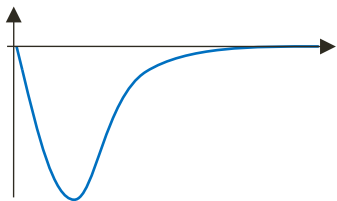


ANALOG FRONT-END BASICS



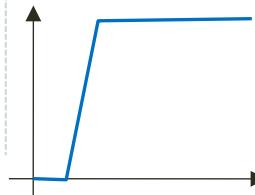
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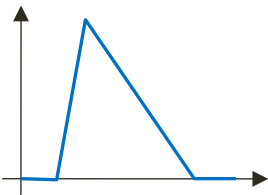
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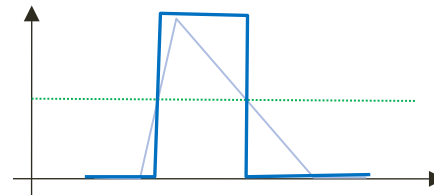
Feedback loop

Discharges the preamplifier after signal rise



Comparator

Compares the signal with the threshold to determine if there was a hit

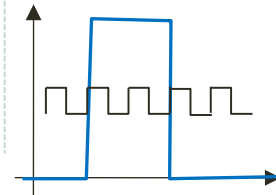


Digital domain

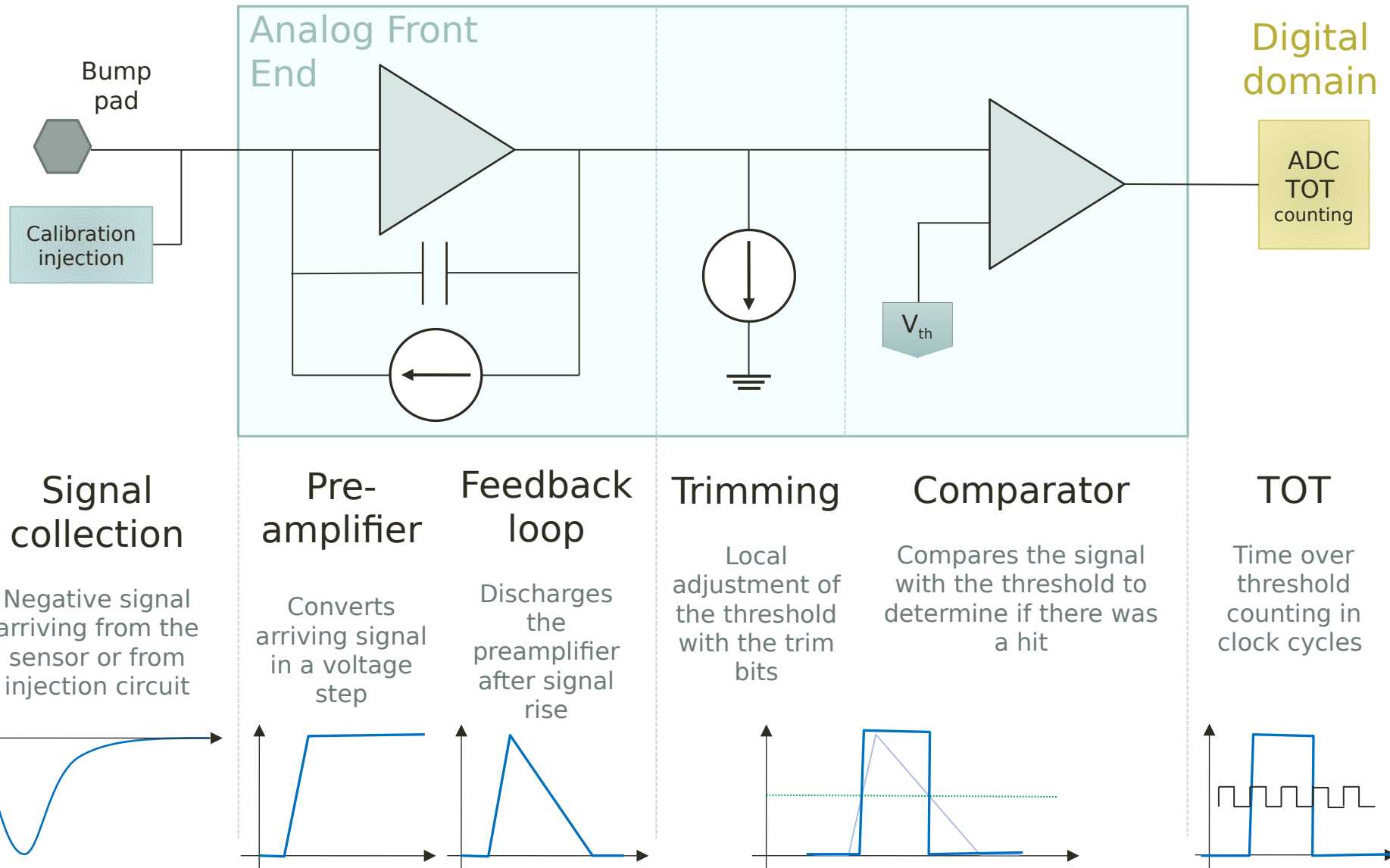
ADC
TOT
counting

TOT

Time over threshold counting in clock cycles



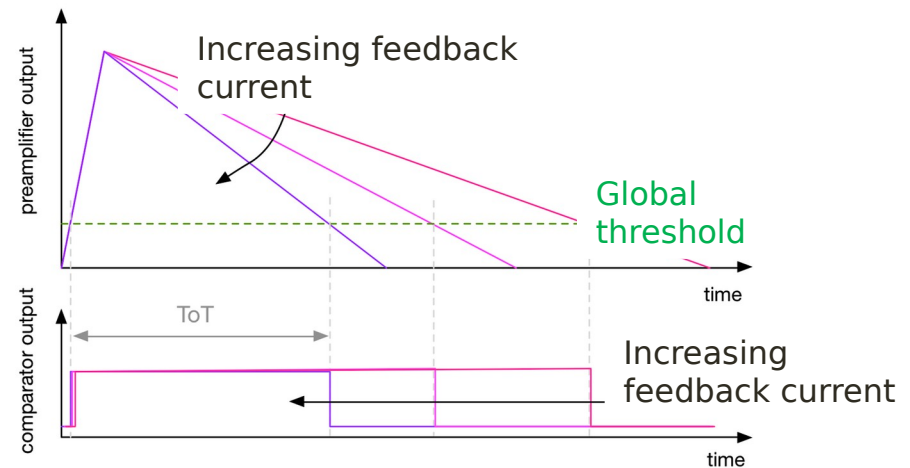
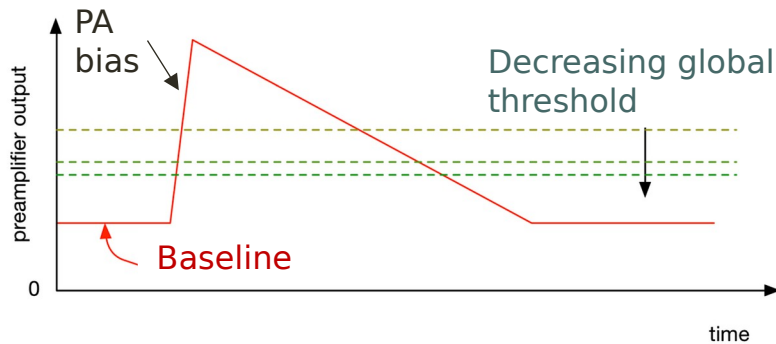
ANALOG FRONT-END BASICS



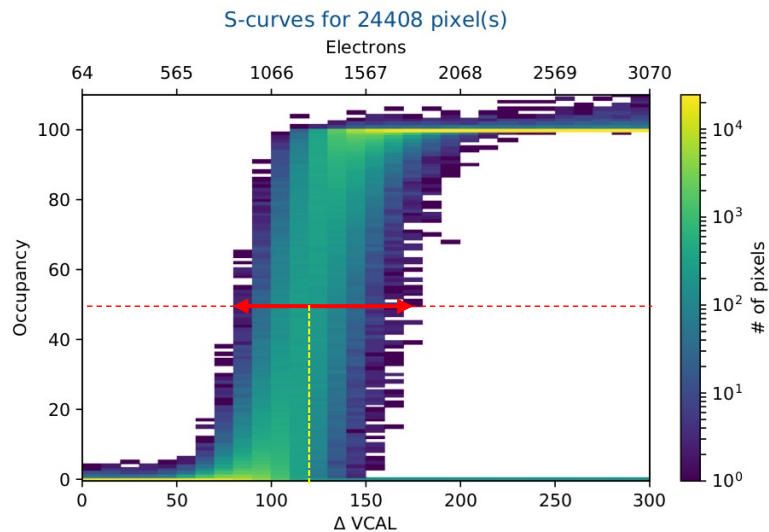
ANALOG FRONT-END PARAMETERS



Global threshold	<i>Sets the global threshold of the comparator</i>
Baseline voltage	<i>Sets the preamplifier output DC baseline</i>
Preamplifier bias	<i>Determines the speed of rise of the signal, main contribution to the power consumption, influence on the noise</i>
Feedback current	<i>Determines the speed of the preamplifier return to baseline and therefore the time over threshold</i>

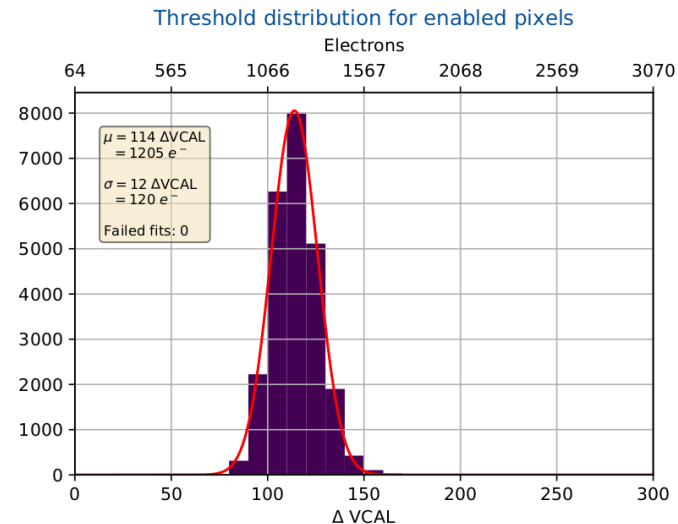


TUNING PROCEDURES



50%
occupancy

slope



Threshold scan

Inject different charges, 100x to every pixel and check number of hits → occupancy

S-curves

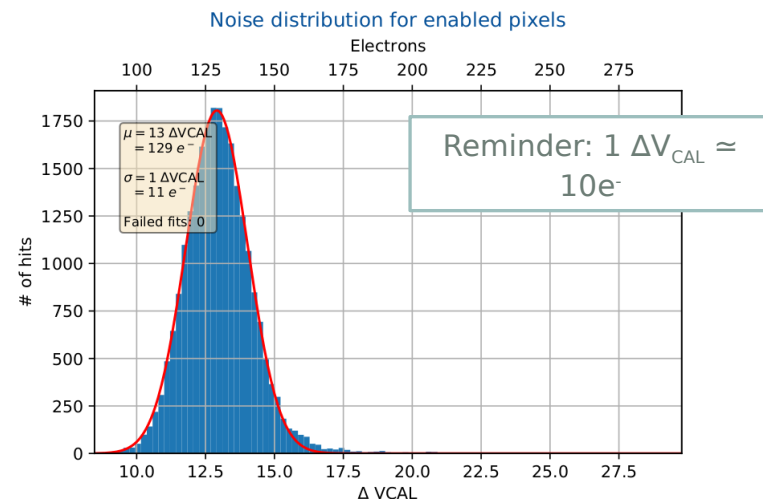
Occupancy vs. injected charge, for every pixel

Threshold

Charge at which 50% occupancy is reached, for every pixel

Equivalent noise charge (ENC)

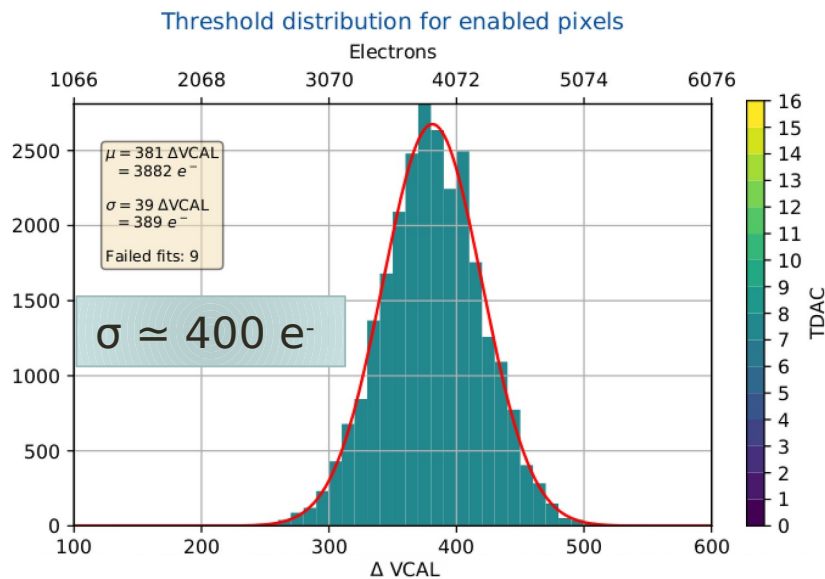
Slope of the s-curve, for each pixel



THRESHOLD TRIMMING

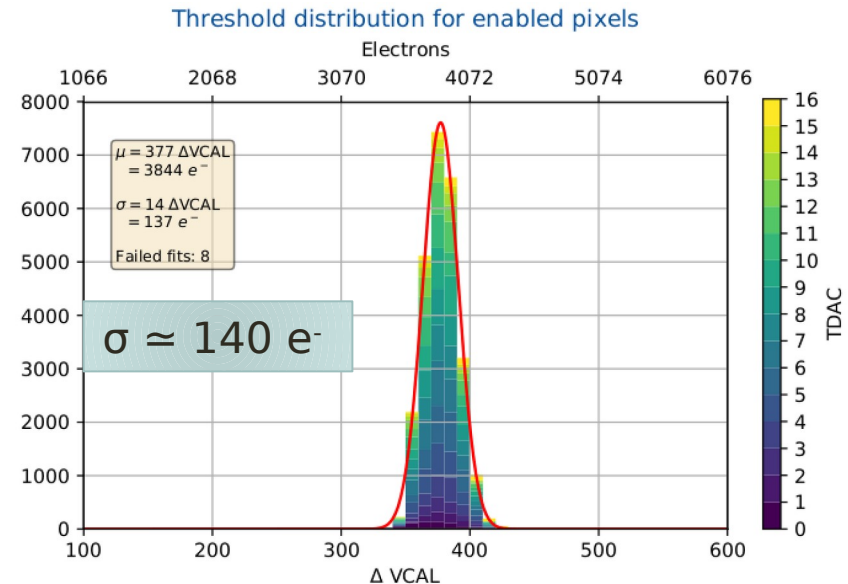


- FE Tuning**
- per pixel local compensation of comparator threshold dispersion
 - set a register in each pixel with a number of **trimming bits** needed to bring local threshold as close as possible to the mean threshold



Before tuning

- All trim bits set to 7
- Wide threshold distribution



After tuning

- Each pixel with a different trim bit (7 as average trim)
- Narrow threshold distribution